



2813

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re. U.S. Patent Application of

HASEGAWA et al.

Application Number: 10/058,787

Filed: January 30, 2002

For: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE,
METHOD OF TESTING SEMICONDUCTOR
INTEGRATED CIRCUIT DEVICE AND METHOD OF
MANUFACTURING SEMICONDUCTOR INTEGRATED
CIRCUIT DEVICE

ATTORNEY DOCKET NO. ASAM.0038

Unit 2813

Examiner
Dolan, Jennifer M

Honorable Assistant Commissioner
for Patents
Washington, D.C. 20231

COVER LETTER

Sir:

[x] The fee for submission of additional claims is calculated as shown below:

FOR	TOTAL WITH NEW CLAIMS ADDED	TOTAL CURRENTLY ON FILE	CLAIMS PAID	RATE	CALCULATION
Total Claims	12	12	(Over 20)	x \$18	0
Independent Claims	3	3	(Over 3)	x \$84	0
MULTIPLE DEPENDENT CLAIM(S)				+ \$280	0
REDUCTION FOR FILING BY SMALL ENTITY (note 37 C.F.R. §§ 1.9, 1.27, 1.28). IF APPLICABLE, VERIFIED STATEMENT MUST BE ATTACHED				x ½	
TOTAL					0

In addition, the below-identified communications are submitted in the above-captioned application or proceeding:

- [x] Response to Office Action (with Claim Amendments) [] Petition for Extension of Time (month)
[] Substitute Specification & marked-up copy [] Terminal Disclaimer
[] Letter to Draftsperson w/ sheets of drawings

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☐ Preliminary Amendment
☐ Other _____

☐ Assignment
☐ Petition under _____

- ☐ Please charge my **Deposit Account Number** _____ in the amount of _____ to cover the fees for _____. A duplicate copy of this paper is enclosed.
- ☐ A check in the amount of \$ _____ to cover the fee is enclosed.
- ☒ The Commissioner is hereby authorized to charge any additional fees associated with this communication, including patent application filing fees and processing fees under 37 C.F.R. § 1.16 and 1.17, or credit any overpayment to **Deposit Account Number 08-1480**.

Respectfully submitted,

Stanley P. Fisher
Registration Number 24,344



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Registration No. 34,072

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September 25, 2003

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Examiner
Dolan, Jennifer M

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10/1/3
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RESPONSE AND AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

This is in response to the Office Action dated September 9, 2003, the period for response to which will expire on October 9, 2003. Applicants hereby timely elect the continuing prosecution of Claims 1-8, without traverse.